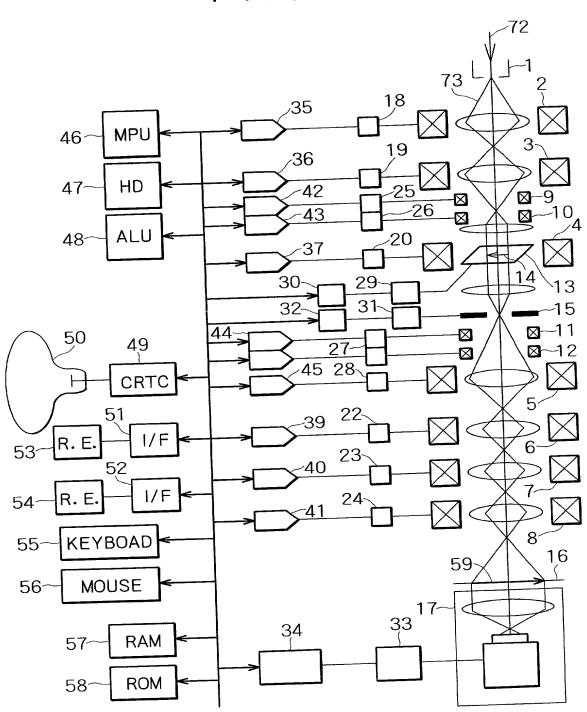
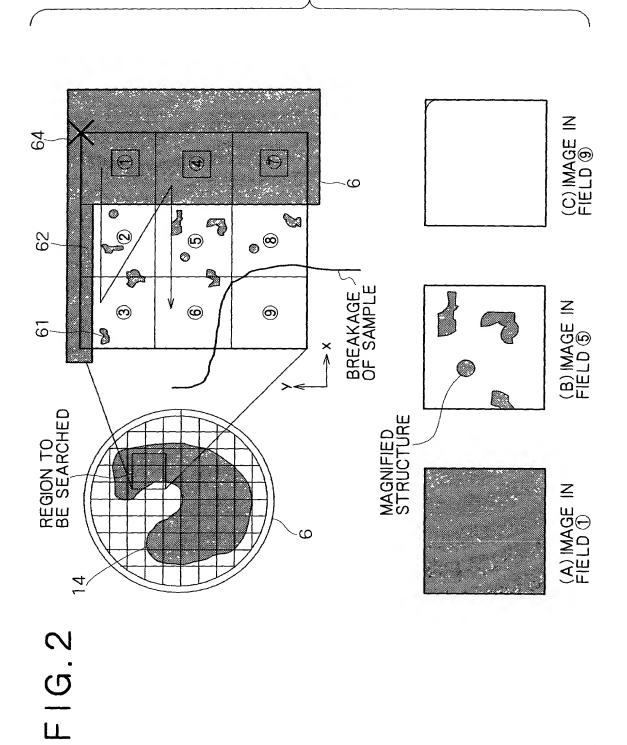
FIG.1





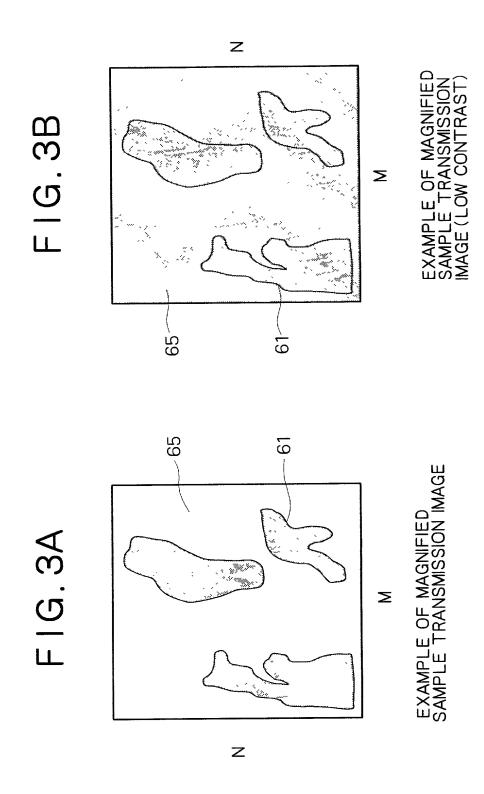


FIG.4

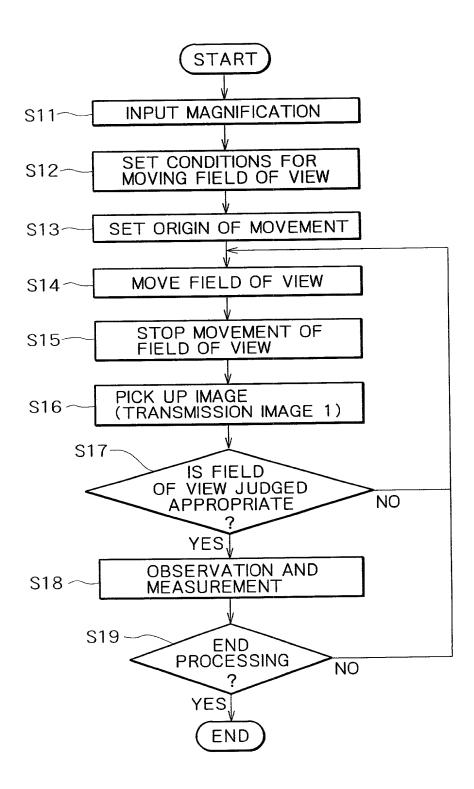
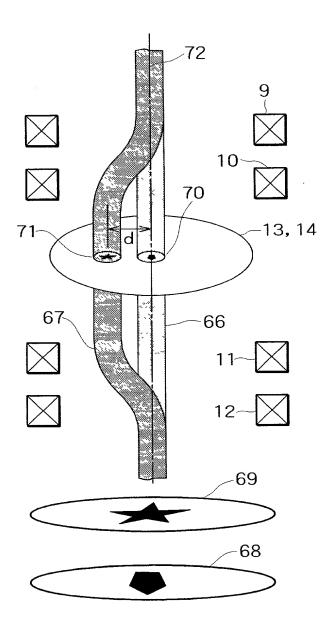
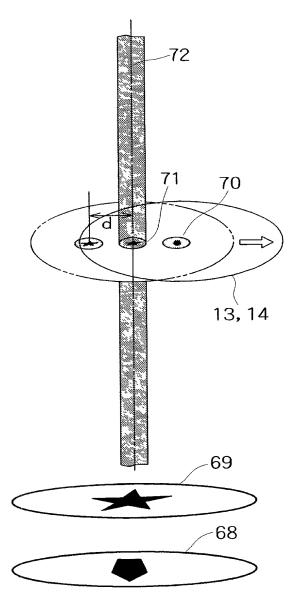


FIG.5A

FIG.5B



ELECTROMAGNETIC MOVEMENT OF FIELD OF VIEW USING ELECTRON BEAM DEFLECTING COIL



MECHANICAL MOVEMENT OF FIELD OF VIEW USING SAMPLE STAGE DRIVER

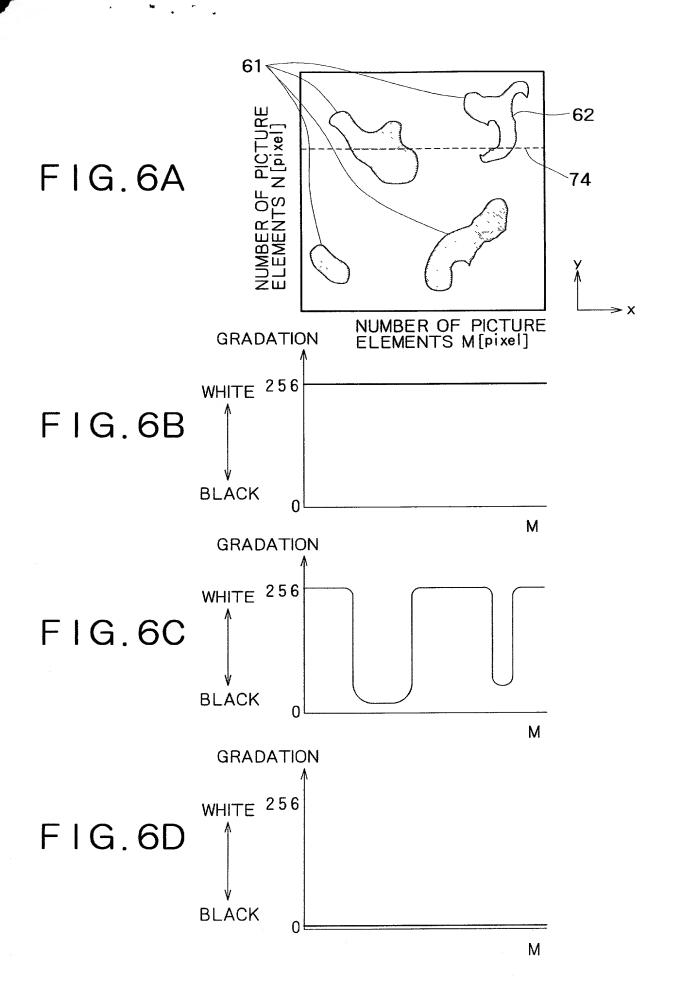


FIG.7

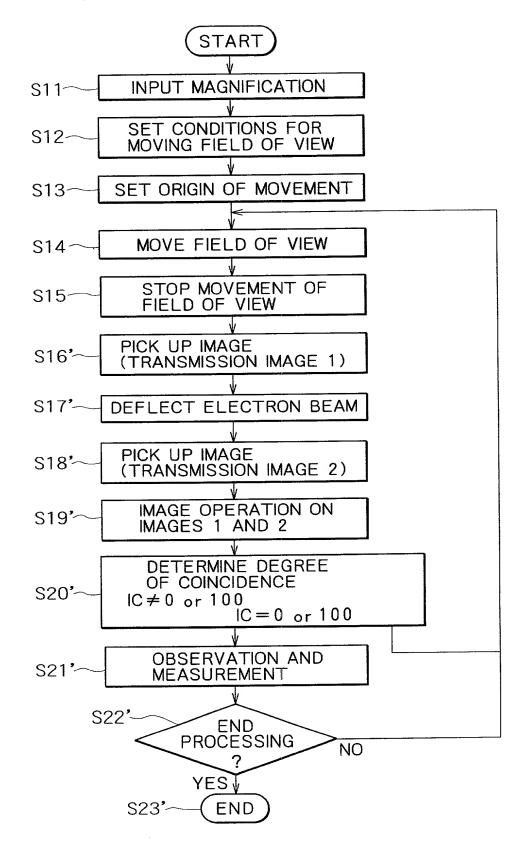
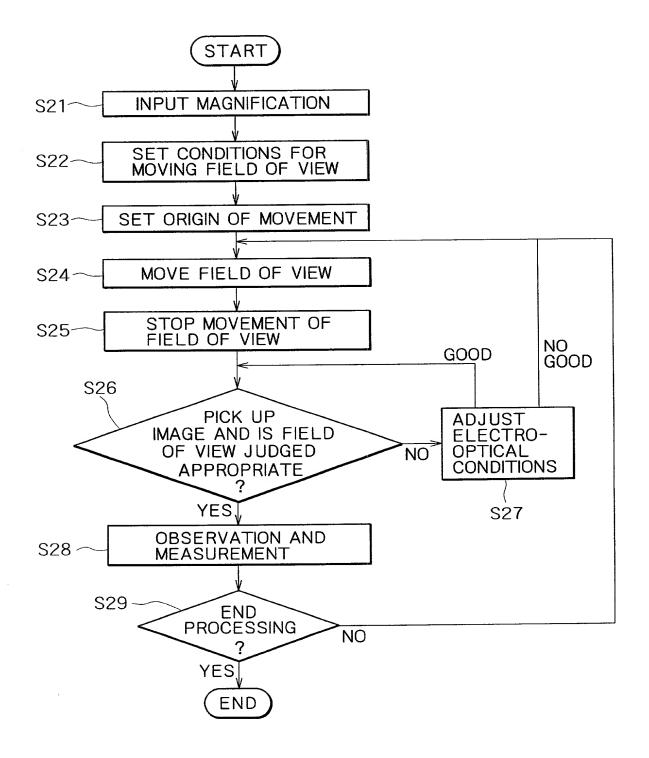
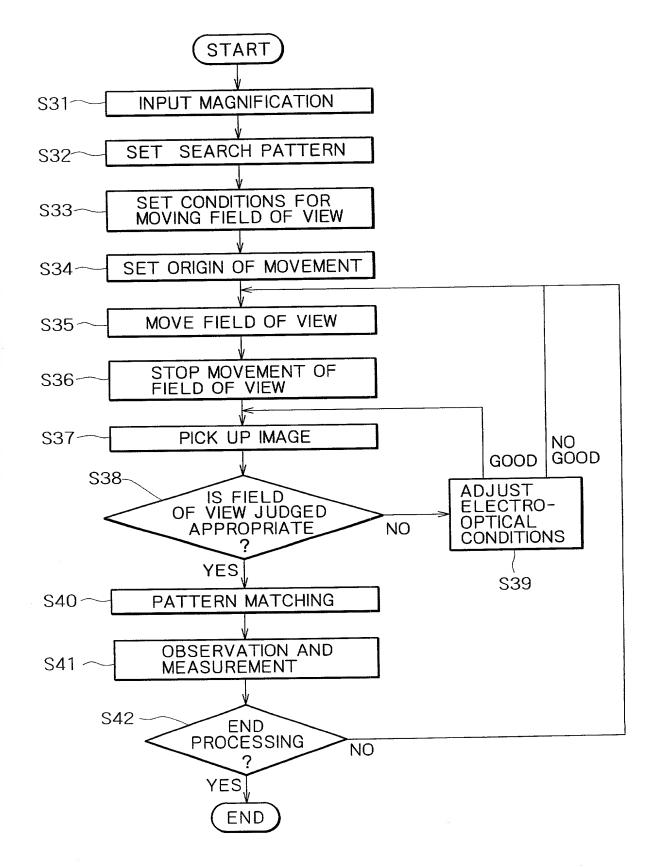


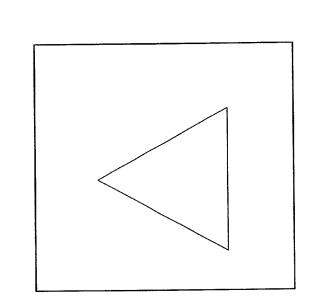
FIG.8



F1G.9

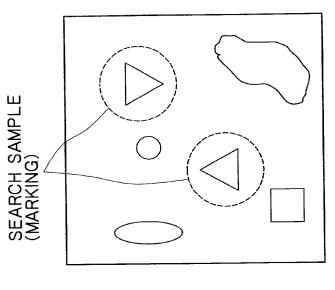


F1G. 10A

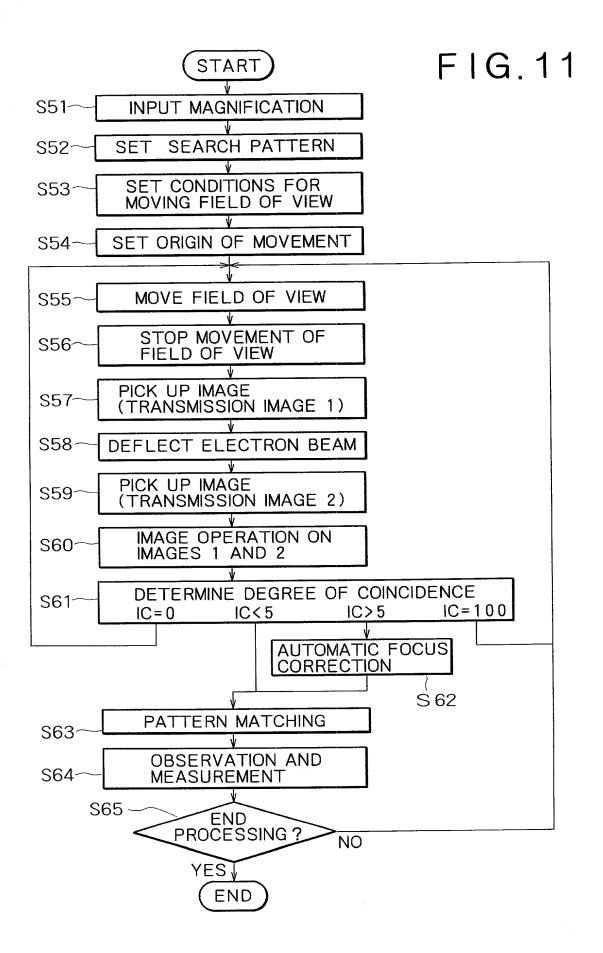


SEARCH TARGET PATTERN

F1G.10B



PICKED-UP FIELD OF VIEW NUMBER OF SEARCH SAMPLES=2



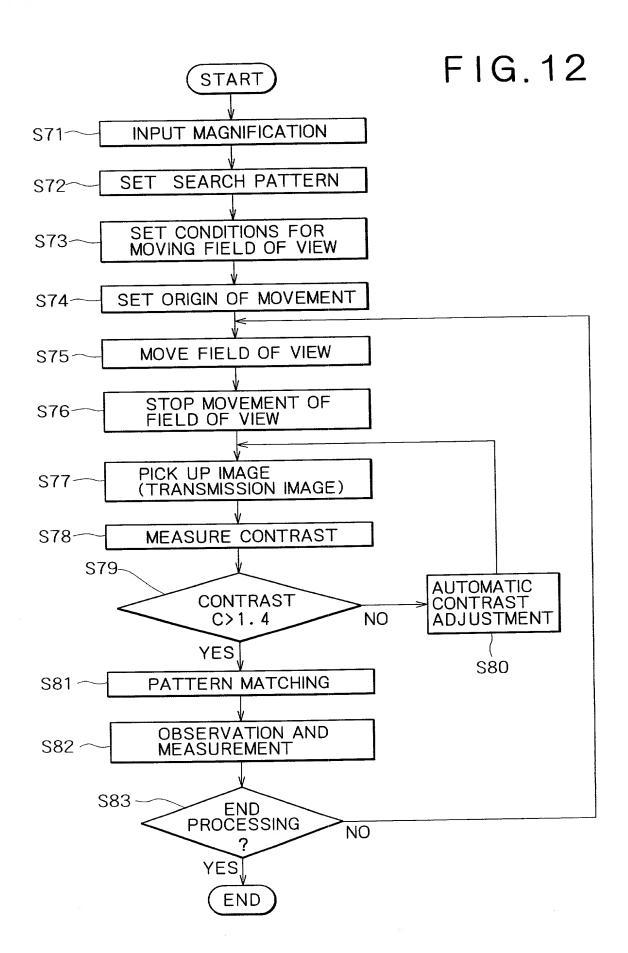
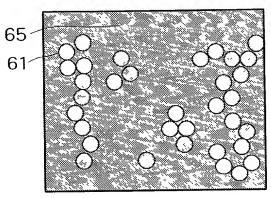
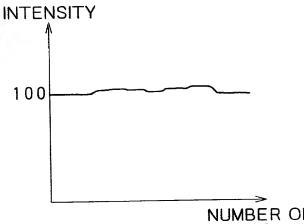


FIG. 13(1)

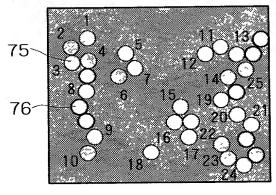


CONTRAST C=1.1



NUMBER OF PIXELS

FIG. 13(2)



CONTRAST C=1.2

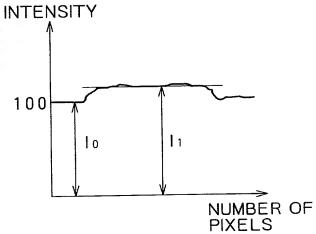
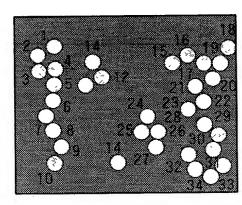
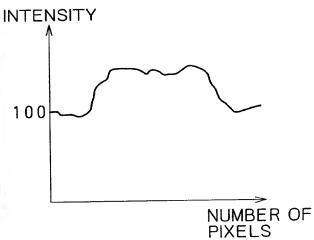


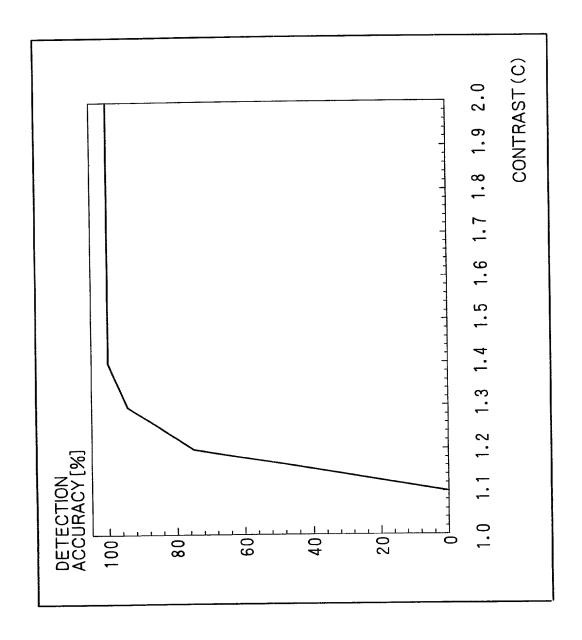
FIG. 13 (3)



CONTRAST C=1.6



F1G.14



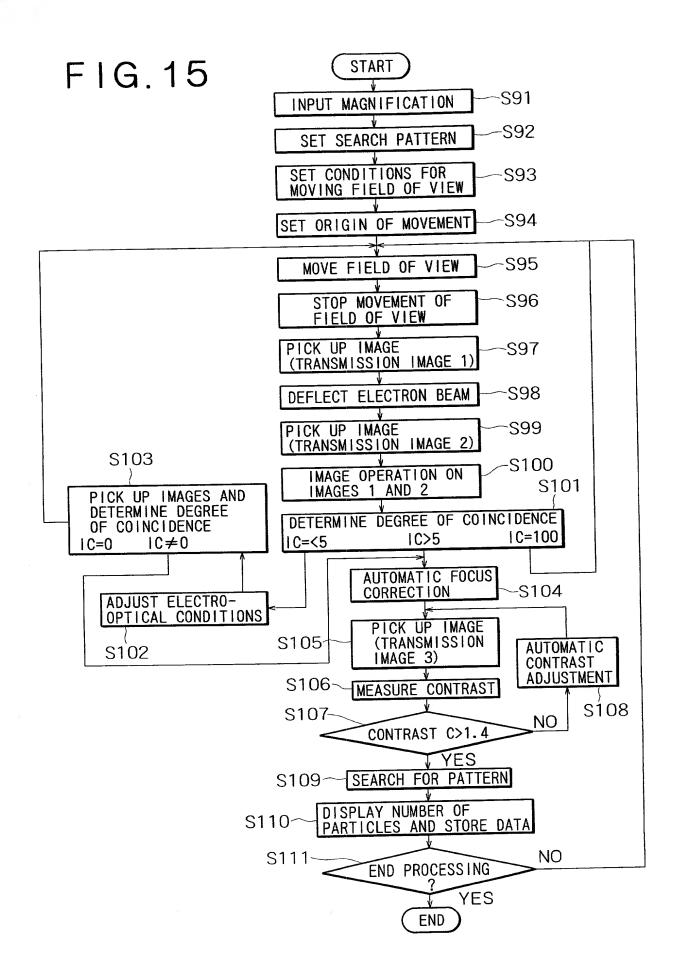


FIG. 16

